

US00D690023S

(12) **United States Design Patent**
Chang et al.

(10) **Patent No.:** **US D690,023 S**

(45) **Date of Patent:** **** Sep. 17, 2013**

(54) **ANALYSIS SYSTEM**

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(**) Term: **14 Years**

(21) Appl. No.: **29/412,457**

(22) Filed: **Feb. 3, 2012**

(51) **LOC (9) Cl.** **24-01**

(52) **U.S. Cl.**
USPC **D24/216**

(58) **Field of Classification Search**
USPC D24/216, 217, 219, 223–226, 231,
D24/232, 107, 169, 186; D10/81; 422/500,
422/547, 62–65, 67; 435/287.1, 287.3; 436/43,
436/45, 47

See application file for complete search history.

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(57) **CLAIM**

The ornamental design for an analysis system, as shown and
described.

DESCRIPTION

FIG. 1 is a perspective view of an analysis system showing
our new design;

FIG. 2 is a front elevational view thereof;

FIG. 3 is a rear elevational view thereof;

FIG. 4 is a left side elevational view thereof;

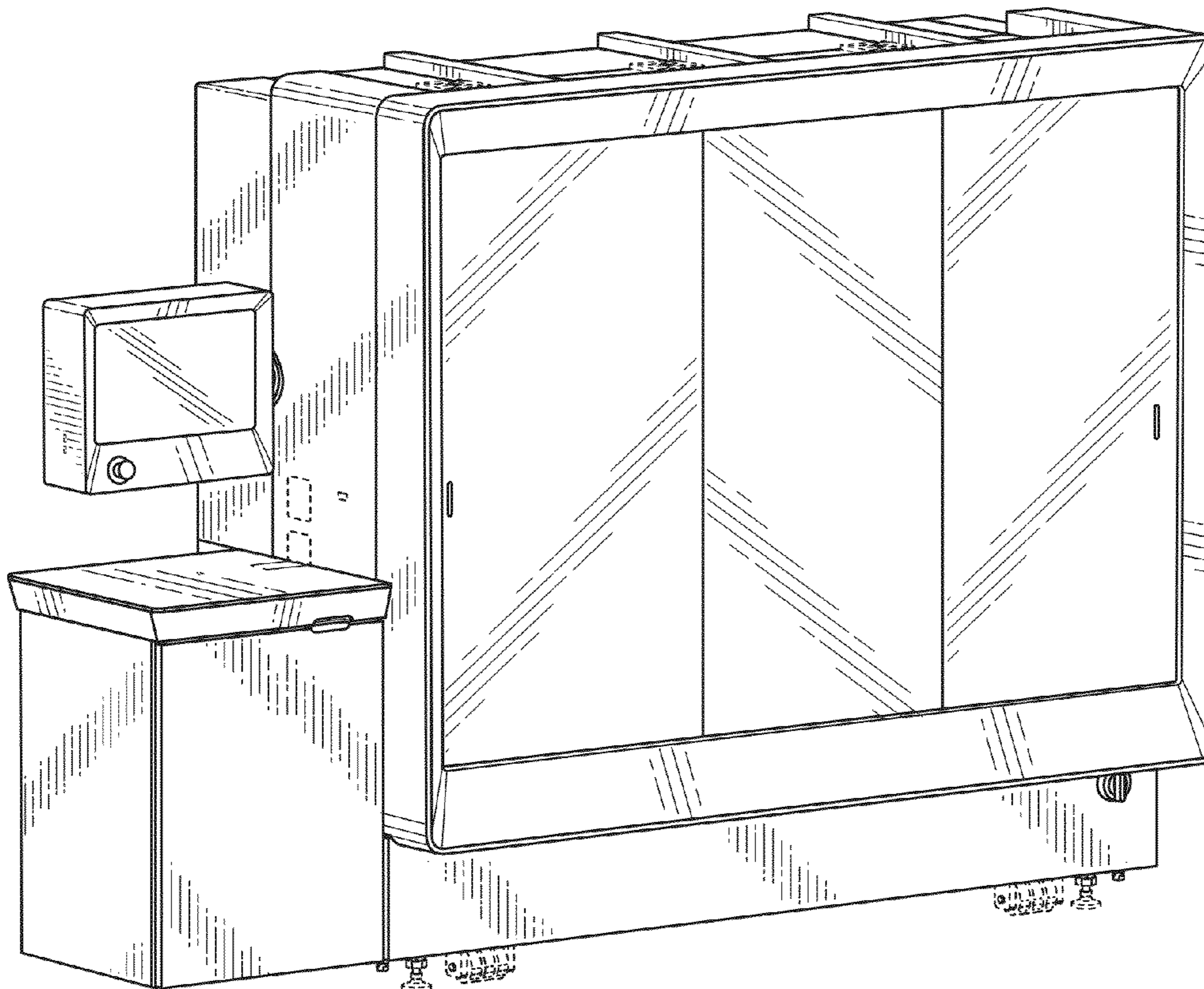
FIG. 5 is a right side elevational view thereof;

FIG. 6 is a top plan view thereof; and,

FIG. 7 is a bottom plan view thereof.

The portions shown in broken lines form no part of the
claimed design.

1 Claim, 5 Drawing Sheets



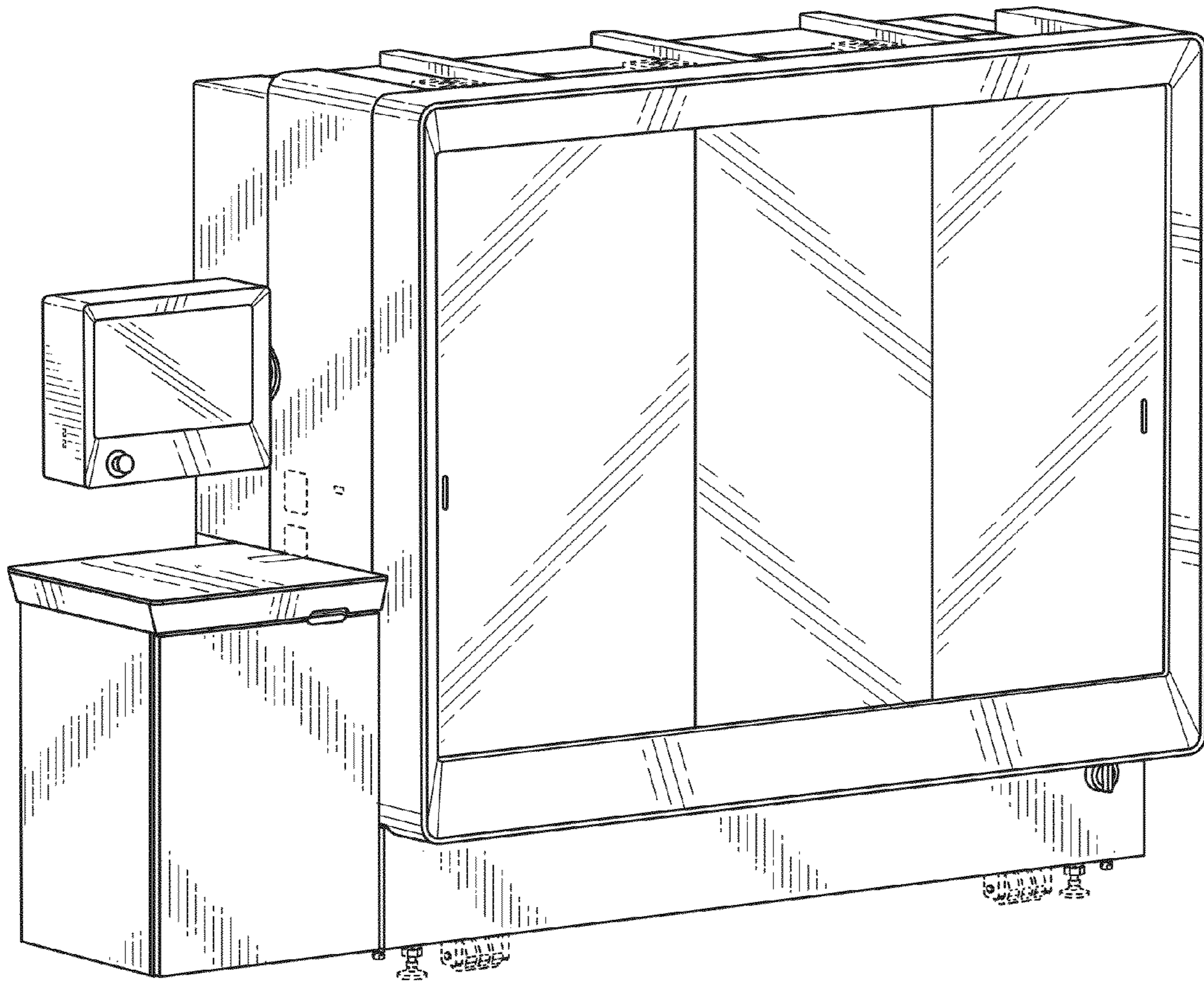


FIG. 1

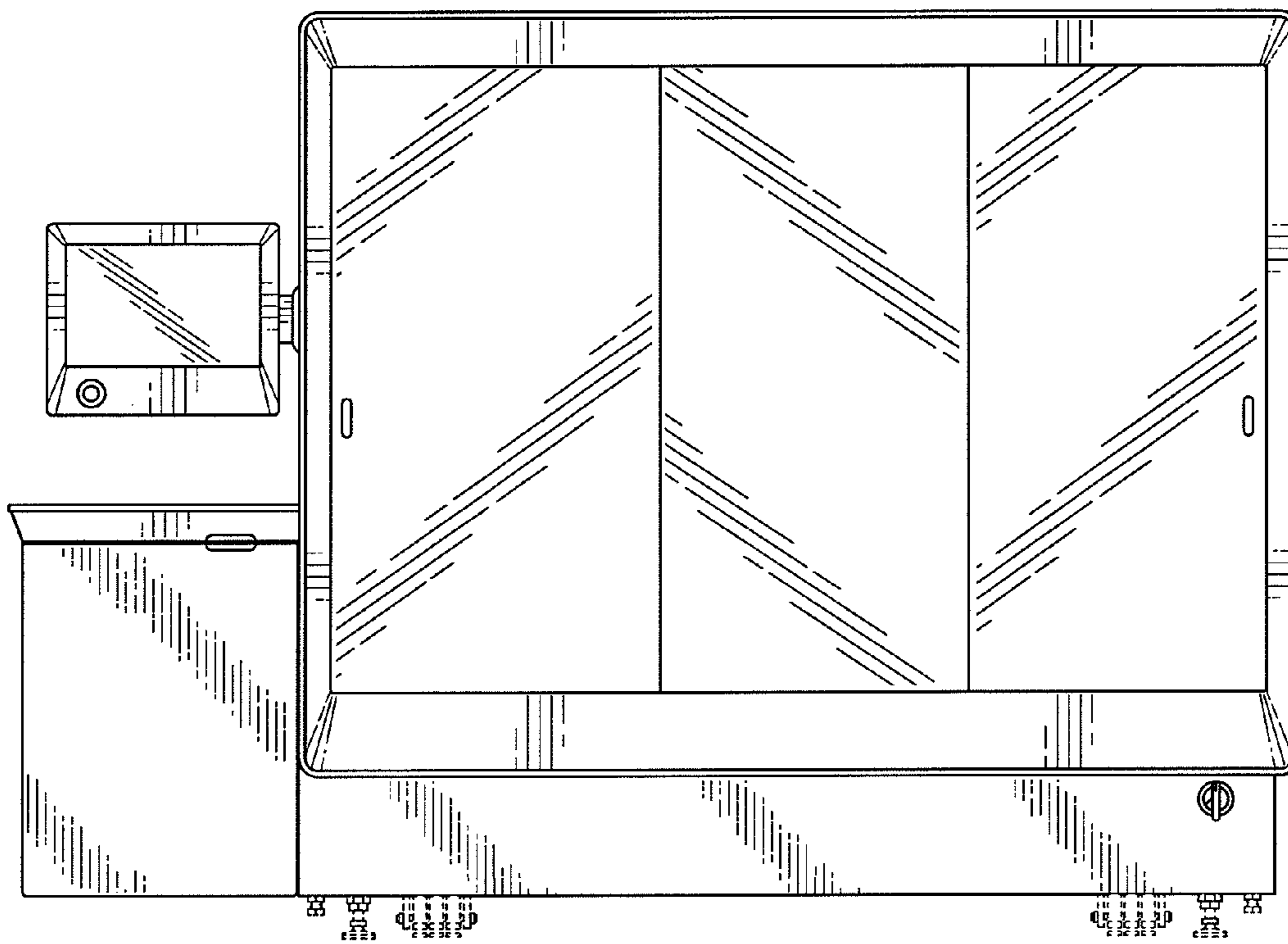


FIG. 2

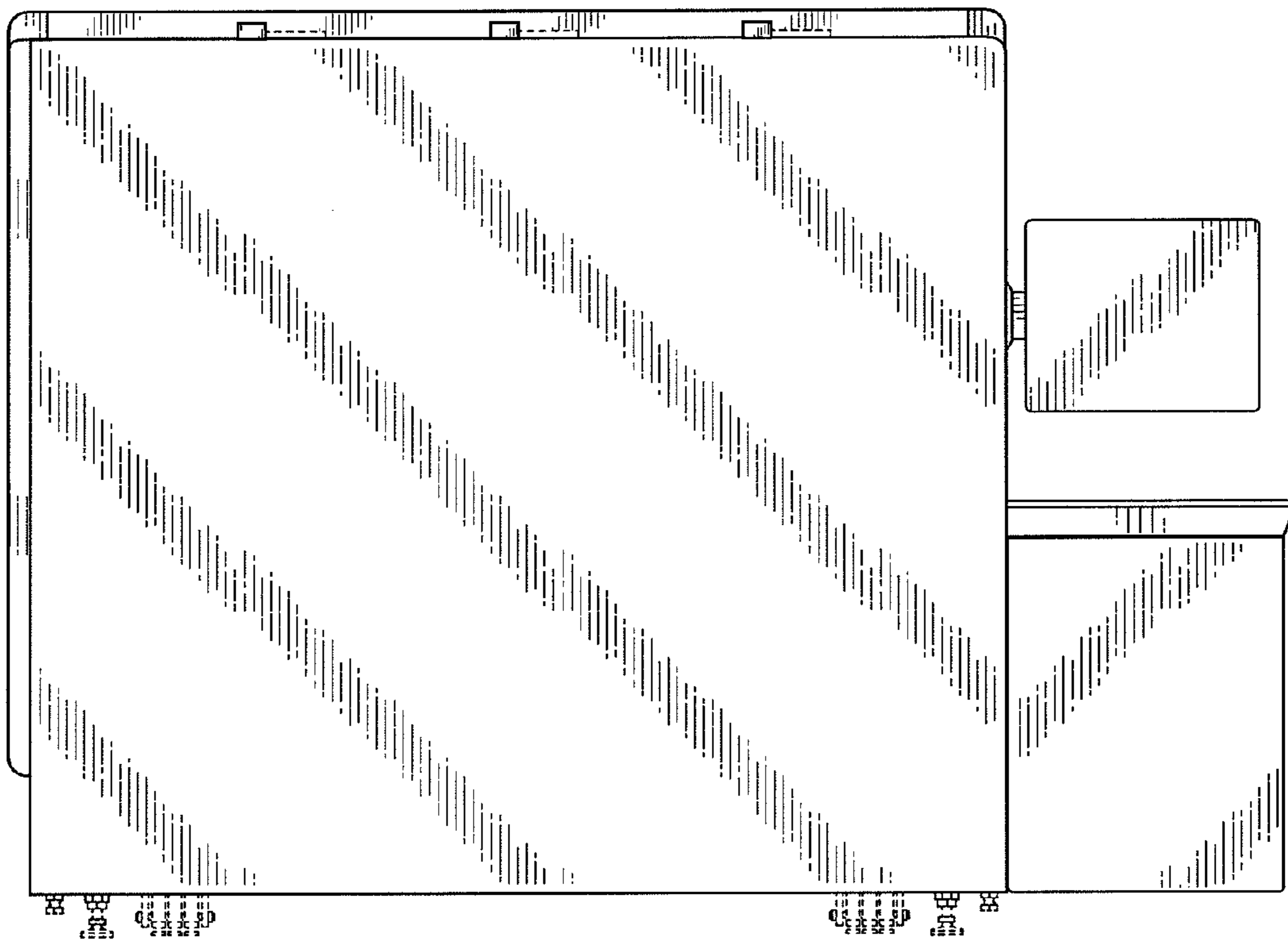


FIG. 3

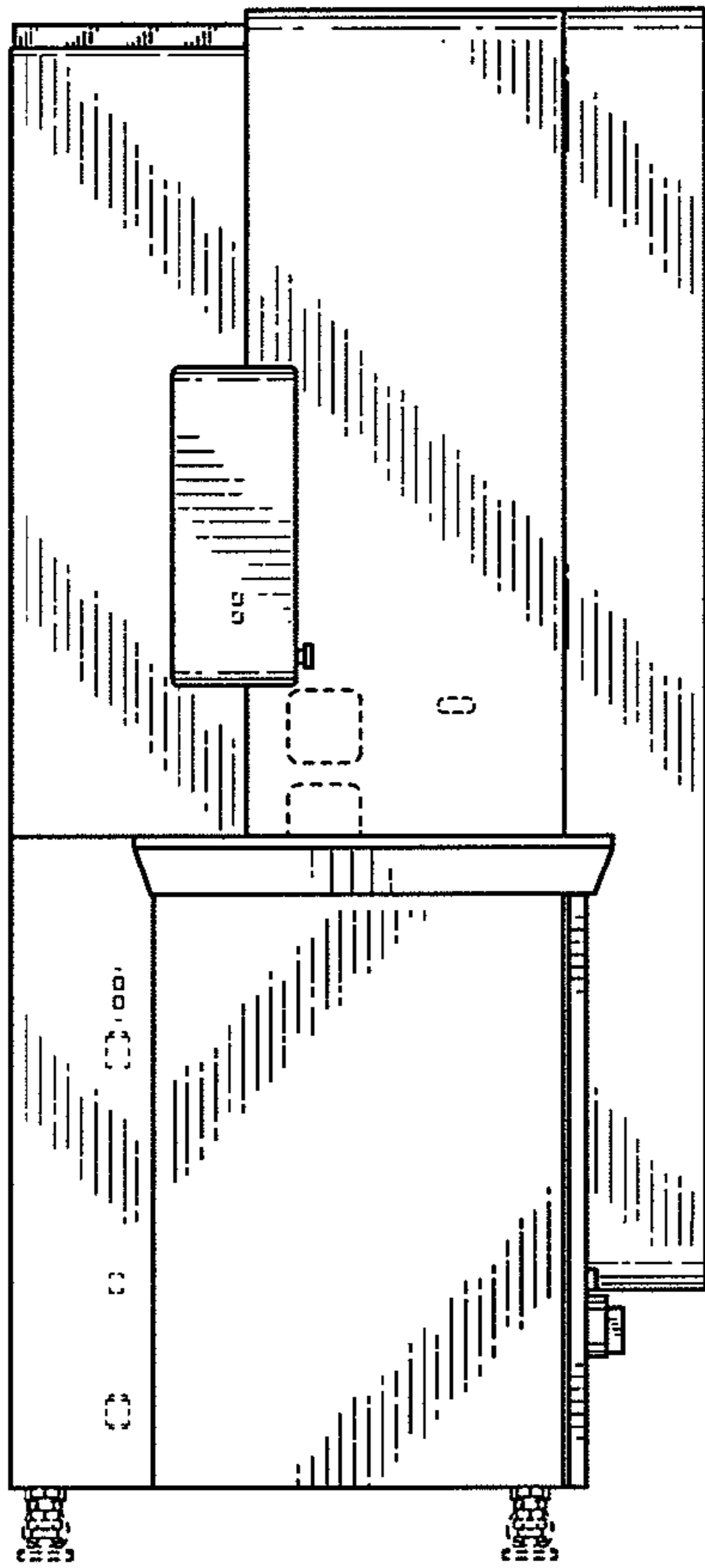


FIG. 4

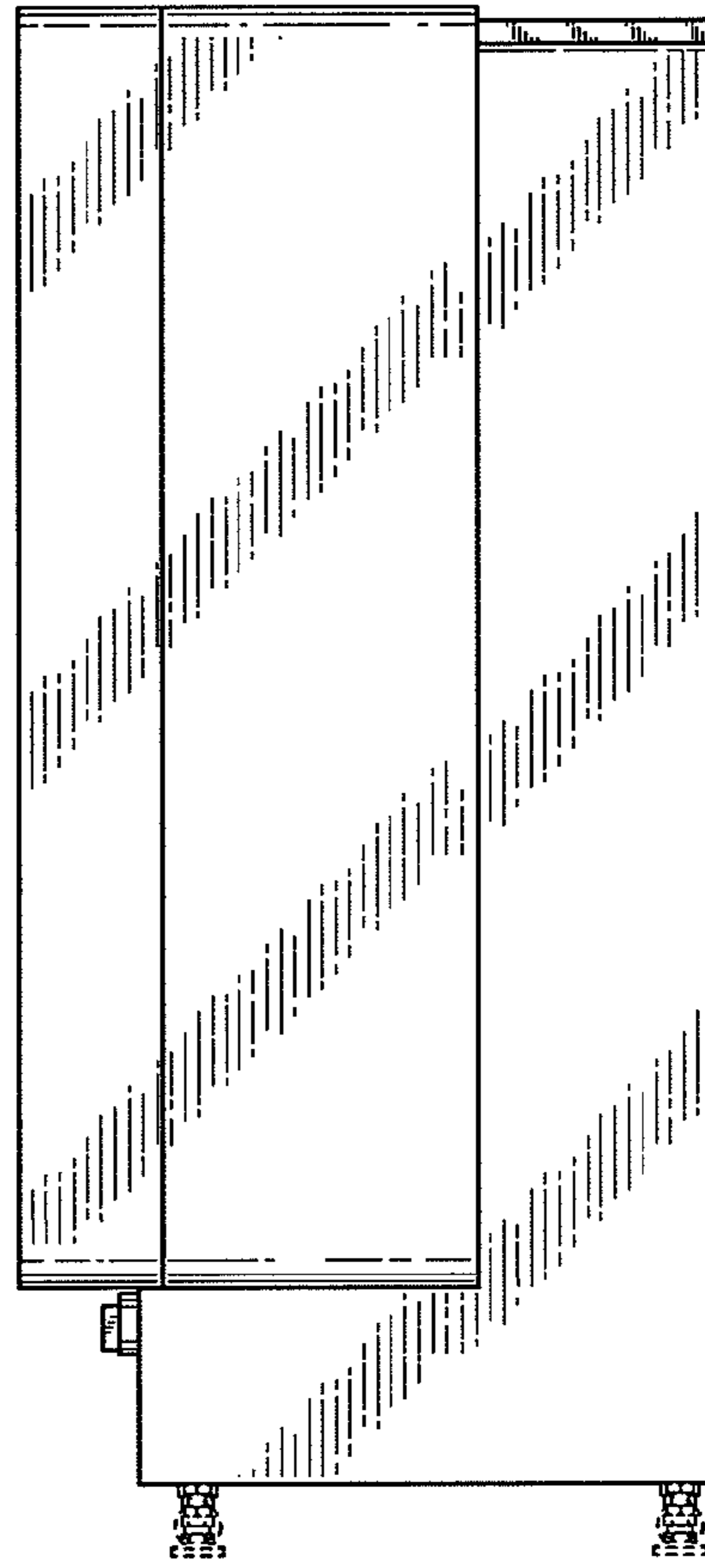


FIG. 5

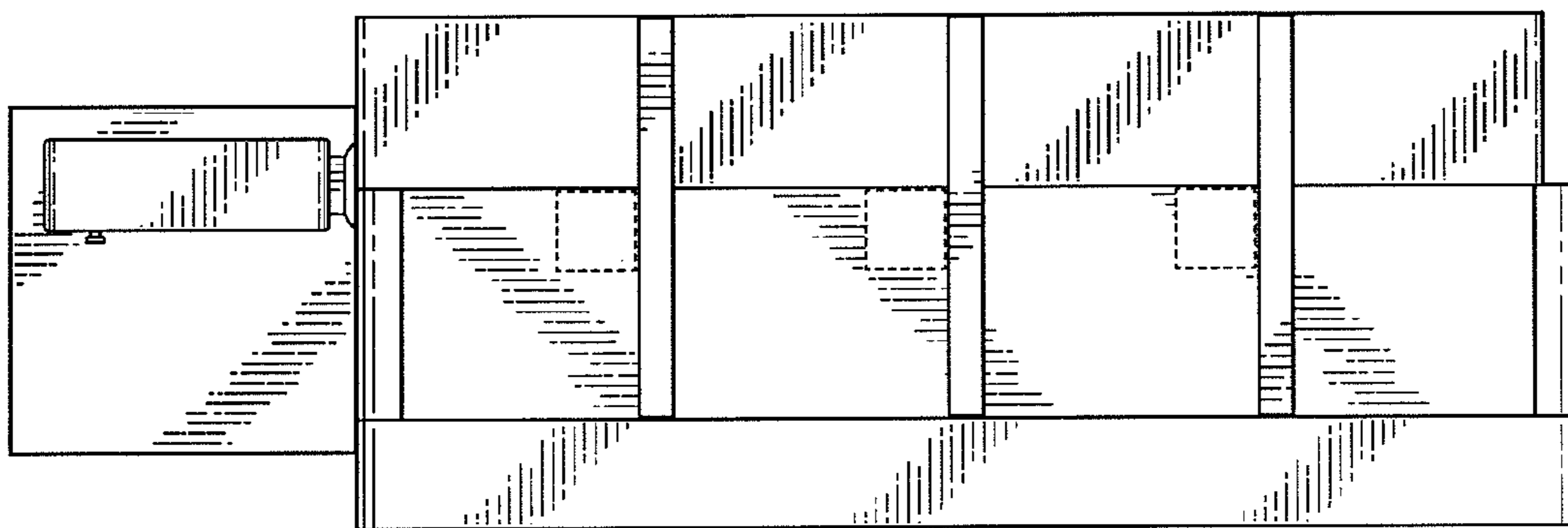


FIG. 6

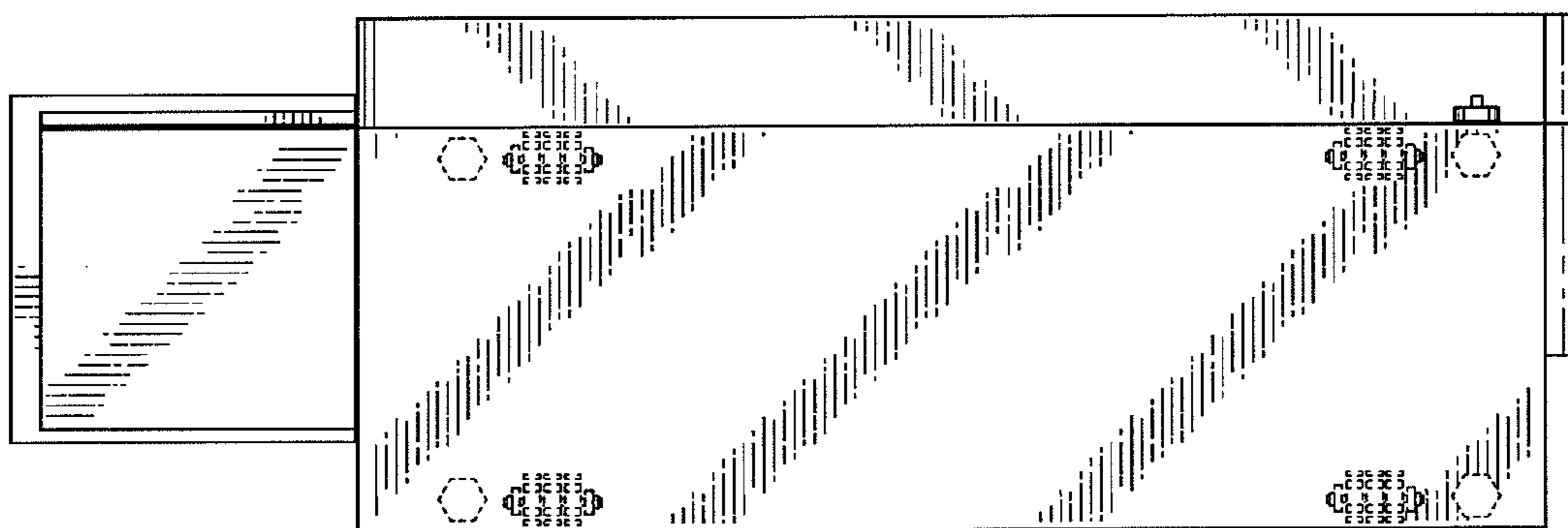


FIG. 7